

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicant:	Hoppe	Docket No.:	QIM 2002 P 50212 US
Serial No.:	10/725,938	Art Unit:	2829
Filed:	December 3, 2003	Examiner:	Nguyen, Vinh P.
For:	Testing Apparatus and Method for Testing the Contacting Between a Semiconductor Device and a Carrier		

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**AMENDMENT**

Dear Sir:

The following amendments and remarks are presented in response to the Examiner's Office Action mailed August 29, 2008. Please amend the above-referenced application as follows.